# **BUK7109-75AIE**

# N-channel TrenchPLUS standard level FET

Rev. 02 — 10 February 2009

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS current sensing and diodes for ElectroStatic Discharge (ESD) protection. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance
- Q101 compliant

- Reduced component count due to integrated current sensor
- Suitable for standard level gate drive sources

### 1.3 Applications

Electrical Power Assisted Steering (EPAS) Variable Valve Timing for engines

### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	75	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 2</u> ; see <u>Figure 3</u>	[1]	-	-	120	Α
Static ch	aracteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 7}}{\text{see } \frac{\text{Figure 8}}{\text{Figure 8}}}$		-	8	9	mΩ
I <sub>D</sub> /I <sub>sense</sub>	ratio of drain current to sense current	$T_j > -55 \text{ °C}; T_j < 175 \text{ °C}; V_{GS} > 10 \text{ V}$		450	500	550	

<sup>[1]</sup> Current is limited by power dissipation chip rating.



### 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		d
2	ISENSE	sense current	mb	
3	D	drain		
4	KS	Kelvin source		
5	S	source	()()3()()	
mb	D	mounting base; connected to	1 2 4 5	
		drain	SOT426 (D2PAK)	s   MBL368

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7109-75AIE	D2PAK	plastic single-ended surface-mounted package (D2PAK); 5 leads (one lead cropped)	SOT426

### 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

		, ,				
Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	75	V
$V_{DGS}$	drain-gate voltage			-	75	V
$V_{GS}$	gate-source voltage			-20	20	V
$I_D$	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; see <u>Figure 2</u> ;	[1]	-	120	Α
		see Figure 3	[2]	-	75	Α
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 10 V; see <u>Figure 2</u>	[2]	-	75	Α
$I_{DM}$	peak drain current	$T_{mb}$ = 25 °C; $t_p \le 10 \mu s$ ; pulsed; see Figure 3		-	480	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>		-	272	W
I <sub>GS(CL)</sub> gate-sou	gate-source clamping	continuous		-	10	mA
	current	pulsed; $t_p = 5 \text{ ms}$ ; $\delta 0.01$		-	50	mA
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dr	ain diode					
Is	source current	T <sub>mb</sub> = 25 °C	[1]	-	120	Α
			[2]	-	75	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	480	Α
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 75 A; $V_{sup} \le$ 75 V; $R_{GS}$ = 50 $\Omega$ ; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	739	mJ
Electrosta	tic discharge					
V <sub>esd</sub>	electrostatic discharge voltage	HBM; C = 100 pF; R = 1.5 kΩ		-	6	kV

<sup>[1]</sup> Current is limited by power dissipation chip rating.

<sup>[2]</sup> Continuous current is limited by package.

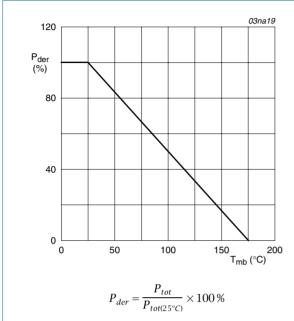


Fig 1. Normalized total power dissipation as a function of mounting base temperature

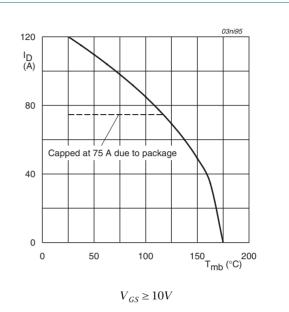
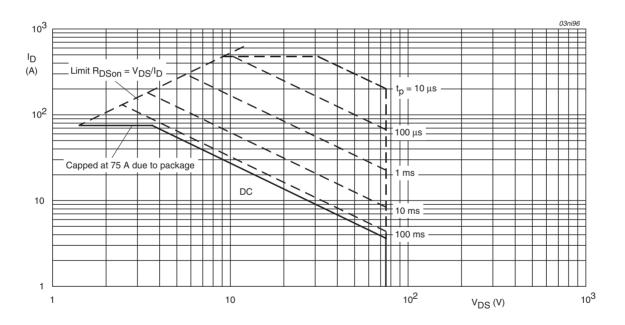


Fig 2. Continuous drain current as a function of mounting base temperature



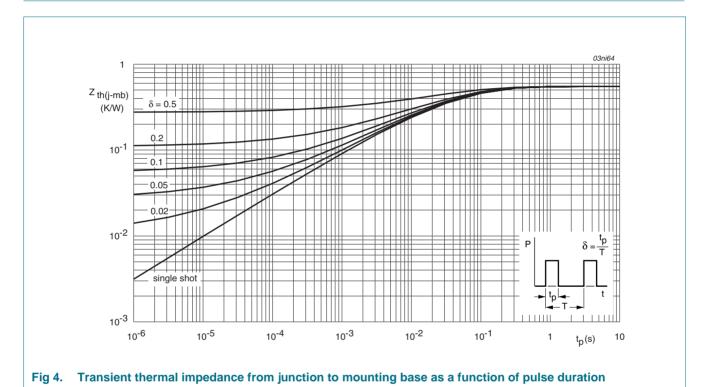
 $T_{mb} = 25$ °C;  $I_{DM}$  is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	minimum footprint; mounted on a printed-circuit board	-	50	-	K/W
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.55	K/W



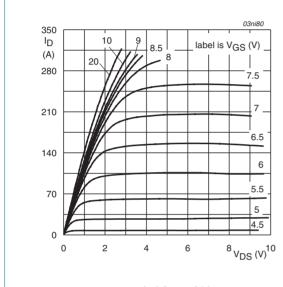
### 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	75	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	70	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see Figure 9	2	3	4	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 175$ °C; see Figure 9	1	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see Figure 9	-	-	4.4	V
DSS	drain leakage current	$V_{DS} = 75 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.1	10	μΑ
		$V_{DS} = 75 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	250	μΑ
V <sub>(BR)GSS</sub> gate-source breakd voltage	gate-source breakdown voltage	$I_G = 1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j > -55 \text{ °C};$ $T_j < 175 \text{ °C}$	20	22	-	V
		$I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j > -55 \text{ °C};$ $T_j < 175 \text{ °C}$	20	22	-	V
GSS	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 \text{ °C}$	-	22	1000	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 \text{ °C}$	-	22	1000	nA
		V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 10 V; T <sub>j</sub> = 175 °C	-	-	10	μΑ
		V <sub>DS</sub> = 0 V; V <sub>GS</sub> = -10 V; T <sub>j</sub> = 175 °C	-	-	10	μΑ
R <sub>DSon</sub>	n drain-source on-state resistance	$V_{GS} = 10 \text{ V}$ ; $I_D = 50 \text{ A}$ ; $T_j = 25 \text{ °C}$ ; see Figure 7; see Figure 8	-	8	9	mΩ
		$V_{GS} = 10 \text{ V}$ ; $I_D = 50 \text{ A}$ ; $T_j = 175 \text{ °C}$ ; see Figure 7; see Figure 8	-	-	19	mΩ
<sub>D</sub> /I <sub>sense</sub>	ratio of drain current to sense current	$V_{GS} > 10 \text{ V; } T_j > -55 \text{ °C; } T_j < 175 \text{ °C}$	450	500	550	
Dynamic o	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 60 \text{ V}; V_{GS} = 10 \text{ V};$	-	121	-	nC
Q <sub>GS</sub>	gate-source charge	T <sub>j</sub> = 25 °C; see <u>Figure 14</u>	-	20	-	nC
$Q_{GD}$	gate-drain charge		-	44	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4700	-	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 12</u>	-	800	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	455	-	pF
d(on)	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	35	-	ns
r	rise time	$R_{G(ext)} = 10 \Omega$ ; $T_j = 25 °C$	-	108	-	ns
d(off)	turn-off delay time		-	185	-	ns
t <sub>f</sub>	fall time		-	100	-	ns
L <sub>D</sub>	internal drain inductance	measured from upper edge of drain mounting base to centre of die; T <sub>j</sub> = 25 °C	-	2.5	-	nΗ
L <sub>S</sub>	internal source inductance	measured from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ

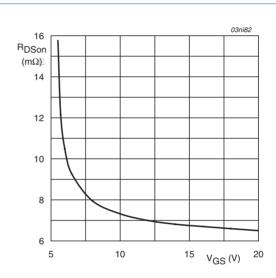
Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 16</u>	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = -10 \text{ V}$ ;	-	75	-	ns
$Q_r$	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	270	-	nC



 $T_j = 25^{\circ}C; t_p = 300 \mu s$ 

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



$$T_j = 25^{\circ}C; I_D = 50A$$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

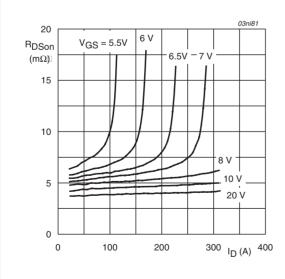
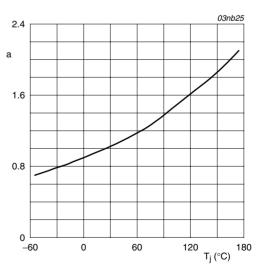


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

 $T_i = 25^{\circ}C; t_p = 300 \mu s$ 



 $a = \frac{R_{DSon}}{R_{DSon(2.5^{\circ}C)}}$ 

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

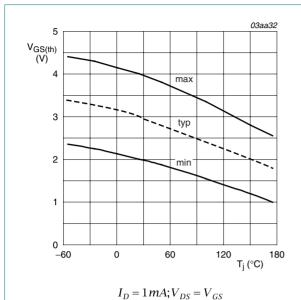
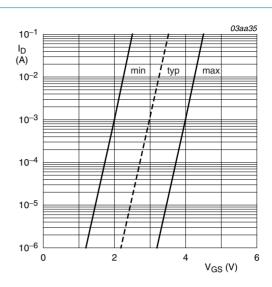
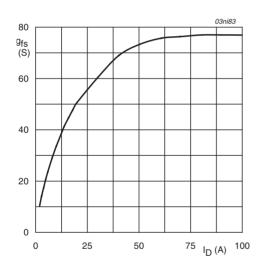


Fig 9. Gate-source threshold voltage as a function of junction temperature



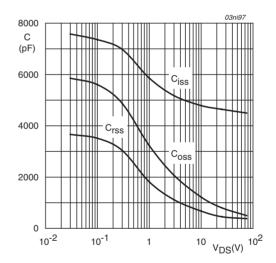
 $T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$ 

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $T_j = 25^{\circ}C; V_{DS} = 25V$ 

Fig 11. Forward transconductance as a function of drain current; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

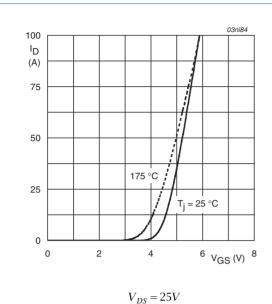


Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values

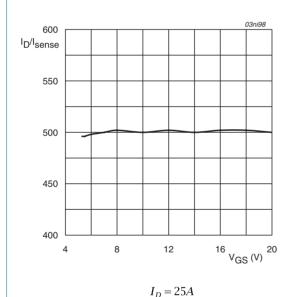
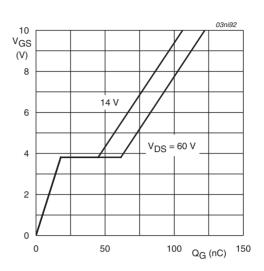


Fig 15. Drain-sense current ratio as a function of gate-source voltage; typical values



 $T_i = 25^{\circ}C; I_D = 25A$ 

Fig 14. Gate-source voltage as a function of turn-on gate charge; typical values

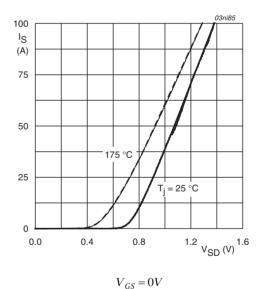


Fig 16. Reverse diode current as a function of reverse diode voltage; typical values

### 7. Package outline

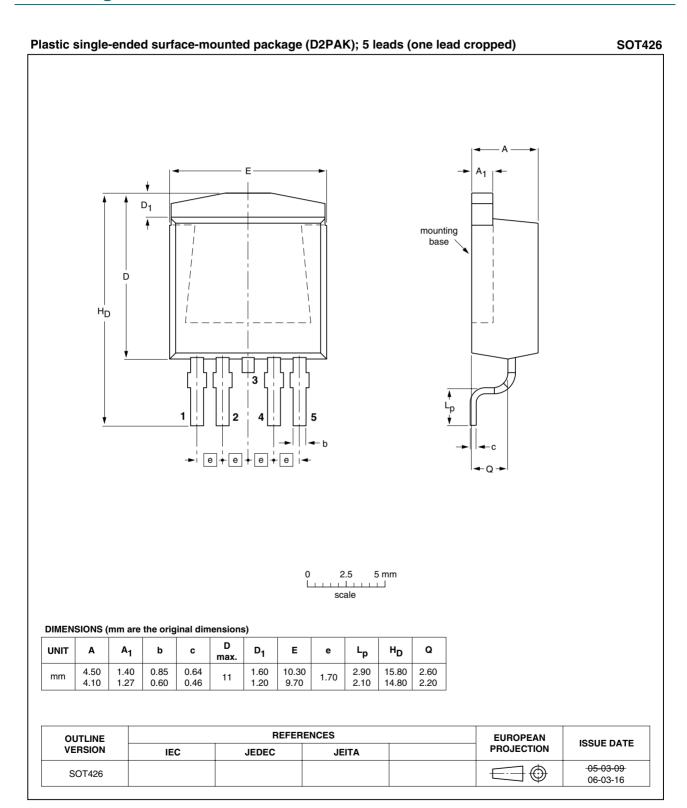


Fig 17. Package outline SOT426 (D2PAK)

### 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7109-75AIE_2	20090210	Product data sheet	-	BUK71_7909_75AIE-01
Modifications:	guidelines • Legal texts	of this data sheet has been of NXP Semiconductors.  have been adapted to the	new company name who	ere appropriate.
BUK71_7909_75AIE-01 (9397 750 09879)	20020809	er BUK7109-75AIE separa Product data sheet	-	-

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#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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# **BUK7109-75AIE**

### N-channel TrenchPLUS standard level FET

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